

P-Channel 100 V (D-S) MOSFET

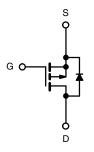
PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)		
- 100	0.040 at V _{GS} = - 10 V	- 37	54 nC		
- 100	0.050 at $V_{GS} = -4.5 \text{ V}$	- 32	34 110		

FEATURES

• TrenchFET® Power MOSFET







P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (TA :	= 25 °C, unless othe	rwise noted)			
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	- 100	V		
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		- 37		
Out in the Davis Out of (T. 150 00)h	T _C = 70 °C	1 . [- 29.5		
Continuous Drain Current (T _J = 150 °C) ^b	T _A = 25 °C	- I _D	- 10 ^{b, c}		
	T _A = 70 °C	1	- 8.2 ^{b, c}	1	
Pulsed Drain Current		I _{DM}	- 150	Α	
Continuous Courses Coursest (Diede Conduction)	T _C = 25 °C	,	- 50 ^a		
Continuous Source Current (Diode Conduction)	T _A = 25 °C	- I _S	- 6.75 ^{b, c}		
Avalanche Current		I _{AS}	- 35		
Single Pulse Avalanche Energy L = 0.1 mH		E _{AS}	61	mJ	
	T _C = 25 °C		113.6		
Mariana Barra Bissinstias	T _C = 70 °C]	72.7	w	
Maximum Power Dissipation	T _A = 25 °C	P _D	6.9 ^{b, c}] vv	
	T _A = 70 °C	1	4.4 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Limit	Unit		
Junction-to-Ambient	PCB Mount (TO-263) ^c	R _{thJA}	40	°C/W		
Junction-to-Case (Drain)		R _{thJC}	2.1	C/VV		

Notes:

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.



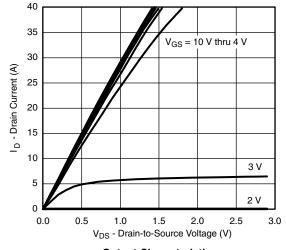
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static					I	1
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	- 100			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A		- 109		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- I _D = - 250 μA		5.9		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 3	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oata Walkana Busin Oamani		V _{DS} = - 100 V, V _{GS} = 0 V			- 1	
Zero Gate Voltage Drain Current	IDSS	V _{DS} = - 100 V, V _{GS} = 0 V, T _J = 55 °C			- 10	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$	- 40			Α
		V _{GS} = - 10 V, I _D = - 9.2 A		0.040		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 7.7 A		0.050		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 9.2 A		38		S
Dynamic ^b	•			•		•
Input Capacitance	C _{iss}			3800		
Output Capacitance	C _{oss}	V _{DS} = - 50 V, V _{GS} = 0 V, f = 1 MHz		185		pF
Reverse Transfer Capacitance	C _{rss}			135		1
Total Gate Charge	Qg	V _{DS} = -50 V, V _{GS} = -10 V, I _D = -9.2 A		106	160	nC
				54	81	
Gate-Source Charge	Q _{gs}	$V_{DS} = -50 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -9.2 \text{ A}$		14		
Gate-Drain Charge	Q_{gd}			26		
Gate Resistance	R_g	f = 1 MHz		4		Ω
Turn-On Delay Time	t _{d(on)}			15	25	
Rise Time	t _r	$V_{DD} = -50 \text{ V}, R_{L} = 6.5 \Omega$		20	30	ns
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -7.7 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		110	165	
Fall Time	t _f			100	150	
Turn-On Delay Time	t _{d(on)}			42	65	
Rise Time	t _r	$V_{DD} = -50 \text{ V}, R_{L} = 6.5 \Omega$		160	240	1
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -7.7 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		100	150	ns
Fall Time	t _f			100	150	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 50	۸
Pulse Diode Forward Current ^a	I _{SM}				- 40	A
Body Diode Voltage	V_{SD}	I _S = - 7.7 A		- 0.8	- 1.2	٧
Body Diode Reverse Recovery Time	t _{rr}			60	90	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = - 7.7 A, dl/dt = 100 A/μs, T _{.I} = 25 °C		150	225	nC
Reverse Recovery Fall Time	t _a	$1_{1F} = -7.7 \text{ A}, \text{ ul/ul} = 100 \text{ A/}\mu\text{s}, 1_{J} = 25 ^{\circ}\text{C}$		46		
Reverse Recovery Rise Time	t _b			14		ns

Notes:

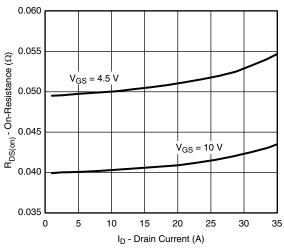
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

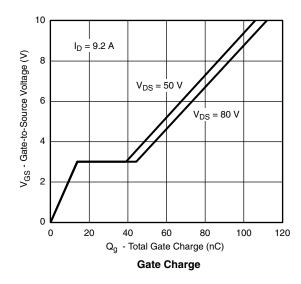


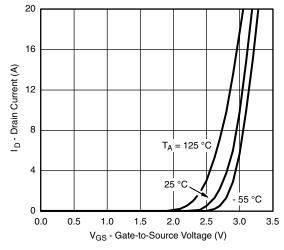


Output Characteristics

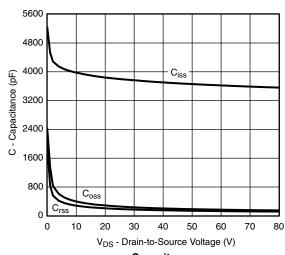


On-Resistance vs. Drain Current and Gate Voltage

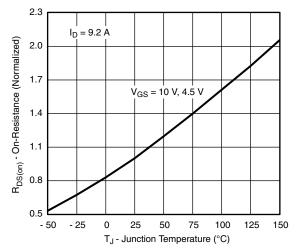




Transfer Characteristics

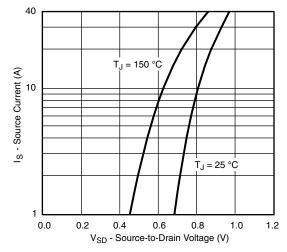


Capacitance

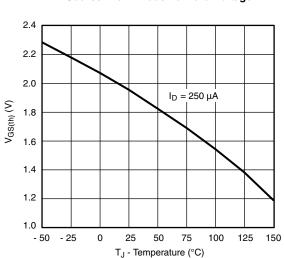


On-Resistance vs. Junction Temperature

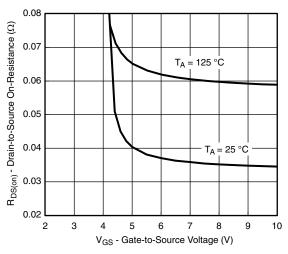




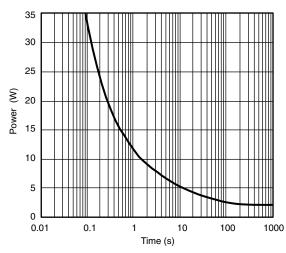




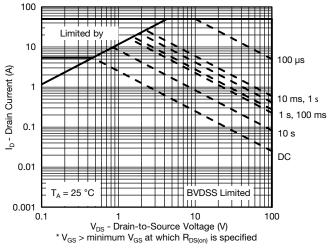
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

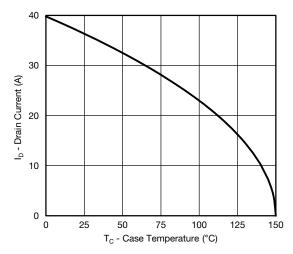


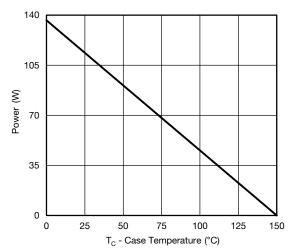
Single Pulse Power, Junction-to-Ambient



Safe Operating Area, Junction-to-Ambient

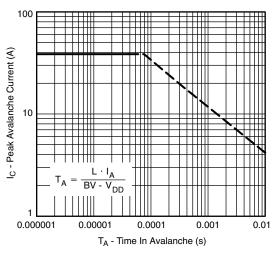






Current Derating*

Single Pulse Power, Junction-to-Ambient

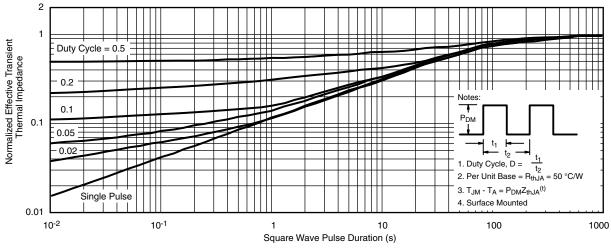


Single Pulse Avalance Capability

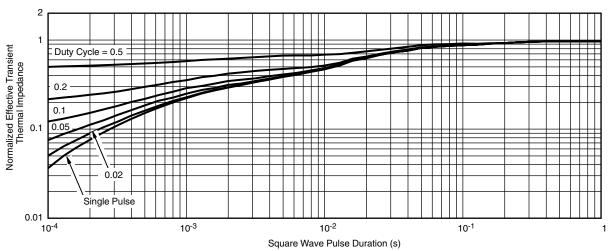
服务热线:400-655-8788 5

^{*} The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





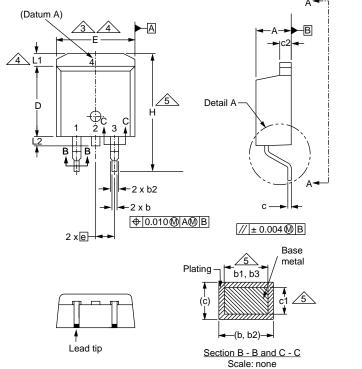
Normalized Thermal Transient Impedance, Junction-to-Ambient

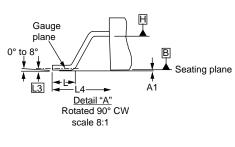


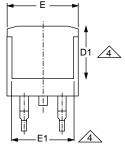
Normalized Thermal Transient Impedance, Junction-to-Case



TO-263AB (HIGH VOLTAGE)







View A - A

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
Е	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
Н	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010	BSC
L4	4.78	5.28	0.188	0.208

ECN: S-82110-Rev. A, 15-Sep-08

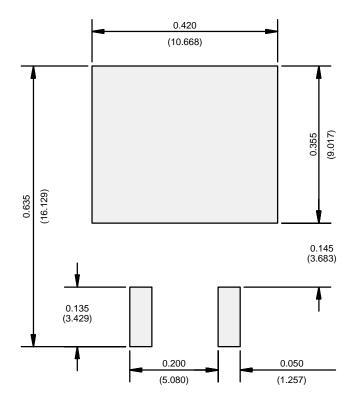
DWG: 5970

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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